Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/666,527	BAILEY ET AL.	
Examiner	Art Unit	
Emmanuel S. Luk	1722	

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Class	Subclass	Date	Examiner
425	174.4	2/6/2006	EL
425	171	2/6/2006	EL
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Class	Subclass	Date	Examiner
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EAST text search	2/6/2006	EL